

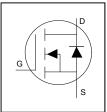
### **Application**

- Brushed Motor drive applications
- BLDC Motor drive applications
- PWM Inverterized topologies
- · Battery powered circuits
- Half-bridge and full-bridge topologies
- Electronic ballast applications
- Synchronous rectifier applications
- Resonant mode power supplies
- OR-ing and redundant power switches
- DC/DC and AC/DC converters

### **Benefits**

- Improved Gate, Avalanche and Dynamic dV/dt Ruggedness
- Fully Characterized Capacitance and Avalanche SOA
- Enhanced body diode dV/dt and dI/dt Capability
- Lead-Free, RoHS Compliant

# HEXFET® Power MOSFET

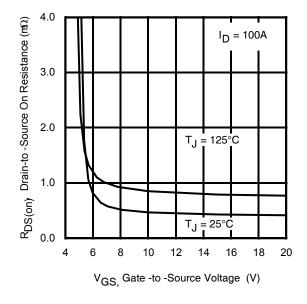


V <sub>DSS</sub>	40V
R <sub>DS(on) typ.</sub>	$0.55$ m $\Omega$
max	$0.75 \mathrm{m}\Omega$
I <sub>D (Silicon Limited)</sub>	<b>522A</b> ①
D (Package Limited)	240A



G	D	S
Gate	Drain	Source

Base next number	Dookogo Typo	Standard Pack		Orderable Part Number
Base part number	Package Type	Form	Quantity	
IDESTAND ZDDNE	430-7PPbF D <sup>2</sup> Pak-7Pin	Tube	50	IRFS7430-7PPbF
IRFS7430-7PPbF	D Fak-/PIII	Tape and Reel Left	800	IRFS7430TRL7PP



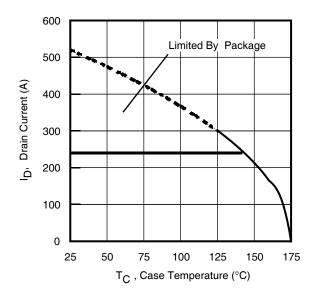


Fig 1. Typical On-Resistance vs. Gate Voltage

Fig 2. Maximum Drain Current vs. Case Temperature



### **Absolute Maximium Rating**

Symbol	Parameter	Max.	Units
$I_D$ @ $T_C$ = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Silicon Limited)	<b>522</b> ①	
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Silicon Limited)	<b>369</b> ①	^
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V (Wire Bond Limited)	240	Α
I <sub>DM</sub>	Pulsed Drain Current ②	1200*	
$P_D @ T_C = 25^{\circ}C$	Maximum Power Dissipation	375	W
	Linear Derating Factor	2.5	W/°C
$V_{GS}$	Gate-to-Source Voltage	± 20	٧
T <sub>J</sub> T <sub>STG</sub>	Operating Junction and Storage Temperature Range	-55 to + 175	°C
	Soldering Temperature, for 10 seconds (1.6mm from case)	300	

### **Avalanche Characteristics**

E <sub>AS (Thermally limited)</sub>	Single Pulse Avalanche Energy ③	764	m l
E <sub>AS (Thermally limited)</sub>	Single Pulse Avalanche Energy 9	1454	mJ
I <sub>AR</sub>	Avalanche Current ②	Coo Fig 15 16 220 22b	Α
E <sub>AR</sub>	Repetitive Avalanche Energy ②	See Fig 15, 16, 23a, 23b	mJ

### **Thermal Resistance**

Symbol	Parameter	Тур.	Max.	Units
$R_{ heta JC}$	Junction-to-Case ®		0.4	°C/\/
$R_{ heta JA}$	Junction-to-Ambient ®		40	°C/W

Static @ T<sub>1</sub> = 25°C (unless otherwise specified)

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	40			V	$V_{GS} = 0V, I_{D} = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient		26		mV/°C	Reference to 25°C, I <sub>D</sub> = 2mA ②
D	Static Drain-to-Source On-Resistance		0.55	0.75	m()	V <sub>GS</sub> = 10V, I <sub>D</sub> = 100A ⑤
$R_{DS(on)}$			0.93		mΩ	$V_{GS} = 6V, I_{D} = 50A$ (§)
$V_{GS(th)}$	Gate Threshold Voltage	2.2	3.0	3.9	V	$V_{DS} = V_{GS}$ , $I_D = 250\mu A$
	Drain to Source Leekage Current			1.0		$V_{DS}$ =40 V, $V_{GS}$ = 0V
I <sub>DSS</sub>	Drain-to-Source Leakage Current			150	μA	$V_{DS} = 40V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
	Gate-to-Source Forward Leakage			100	nA	V <sub>GS</sub> = 20V
I <sub>GSS</sub>	Gate-to-Source Reverse Leakage			-100	IIA	$V_{GS} = -20V$
$R_G$	Gate Resistance		2.2		Ω	

#### Notes:

- ① Calculated continuous current based on maximum allowable junction temperature. Bond wire current limit is 240A by source bonding technology. Note that current limitations arising from heating of the device leads may occur with some lead mounting arrangements. (Refer to AN-1140)
- ② Repetitive rating; pulse width limited by max. junction temperature.
- 3 Limited by  $T_{Jmax}$ , starting  $T_J$  = 25°C, L = 153 $\mu$ H,  $R_G$  = 50 $\Omega$ ,  $I_{AS}$  = 100A,  $V_{GS}$  =10V.
- $\bigcirc$  Pulse width  $\leq 400 \mu s$ ; duty cycle  $\leq 2\%$ .
- ©  $C_{oss}$  eff. (TR) is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$ .
- $\odot$  C<sub>oss</sub> eff. (ER) is a fixed capacitance that gives the same energy as C<sub>oss</sub> while V<sub>DS</sub> is rising from 0 to 80% V<sub>DSS</sub>.
- 9 Limited by  $T_{Jmax}$ , starting  $T_J = 25$ °C, L = 1mH,  $R_G = 50\Omega$ ,  $I_{AS} = 54A$ ,  $V_{GS} = 10V$ .
- When mounted on 1" square PCB (FR-4 or G-10 Material). Please refer to AN-994 for more details: <a href="http://www.irf.com/technical-info/appnotes/an-994.pdf">http://www.irf.com/technical-info/appnotes/an-994.pdf</a>
- \* Pulse drain current is limited at 960A by source bonding technology.



## Dynamic Electrical Characteristics @ $T_J$ = 25°C (unless otherwise specified)

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
gfs	Forward Transconductance	176			S	$V_{DS} = 10V, I_{D} = 100A$
$Q_g$	Total Gate Charge		305	460		I <sub>D</sub> = 100A
$Q_{gs}$	Gate-to-Source Charge		84		nC	V <sub>DS</sub> = 20V
$Q_{gd}$	Gate-to-Drain Charge		96		IIC	V <sub>GS</sub> = 10V⑤
Q <sub>sync</sub>	Total Gate Charge Sync. (Qg- Qgd)		209			
$t_{d(on)}$	Turn-On Delay Time		28			V <sub>DD</sub> = 20V
t <sub>r</sub>	Rise Time		79			I <sub>D</sub> = 30A
t <sub>d(off)</sub>	Turn-Off Delay Time		161		ns	$R_G = 2.7\Omega$
t <sub>f</sub>	Fall Time		93			V <sub>GS</sub> = 10V⑤
C <sub>iss</sub>	Input Capacitance		13975			V <sub>GS</sub> = 0V
C <sub>oss</sub>	Output Capacitance		2140			V <sub>DS</sub> = 25V
$C_{rss}$	Reverse Transfer Capacitance		1438		pF	f = 1.0MHz, See Fig.7
Coss eff.(ER)	Effective Output Capacitance (Energy Related)		2620			V <sub>GS</sub> = 0V, VDS = 0V to 32V⑦ See Fig.11
Coss eff.(TR)	Output Capacitance (Time Related)		3306			V <sub>GS</sub> = 0V, VDS = 0V to 32V⑥

## **Diode Characteristics**

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current (Body Diode) ①			<b>522</b> ①		MOSFET symbol showing the
I <sub>SM</sub>	Pulsed Source Current (Body Diode) ①			1200*		integral reverse p-n junction diode.
$V_{SD}$	Diode Forward Voltage		0.8	1.2	V	$T_J = 25^{\circ}C, I_S = 100A, V_{GS} = 0V $ §
dv/dt	Peak Diode Recovery dv/dt⊕		1.6		V/ns	$T_J = 175^{\circ}C, I_S = 100A, V_{DS} = 40V$
4	Deverse Decement Time		50		no	$T_{J} = 25^{\circ}C \qquad V_{DD} = 34V$
t <sub>rr</sub>	Reverse Recovery Time		58		ns	$T_J = 125^{\circ}C$ $I_F = 100A$ ,
	Deverse December Charge		59		200	$T_J = 25^{\circ}C$ di/dt = 100A/µs \$
$Q_{rr}$	Reverse Recovery Charge		72		nC	<u>T<sub>J</sub> = 125°C</u>
I <sub>RRM</sub>	Reverse Recovery Current		2.2		Α	T <sub>J</sub> = 25°C



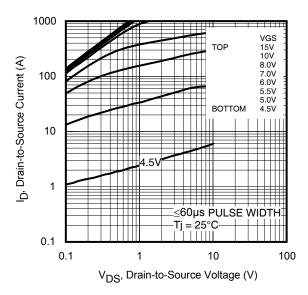


Fig 3. Typical Output Characteristics

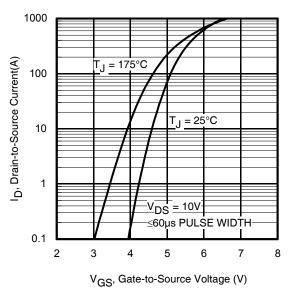


Fig 5. Typical Transfer Characteristics

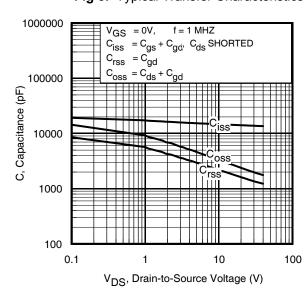


Fig 7. Typical Capacitance vs. Drain-to-Source Voltage

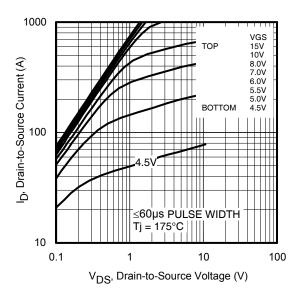


Fig 4. Typical Output Characteristics

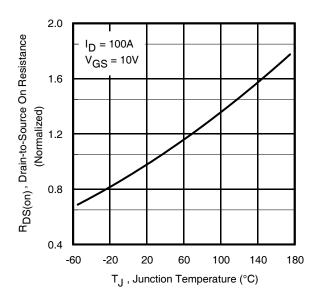


Fig 6. Normalized On-Resistance vs. Temperature

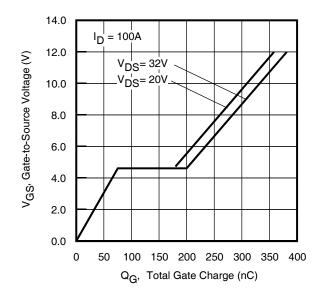


Fig 8. Typical Gate Charge vs. Gate-to-Source Voltage



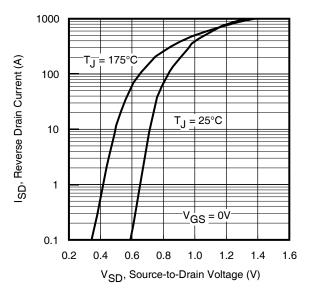


Fig 9. Typical Source-Drain Diode Forward Voltage

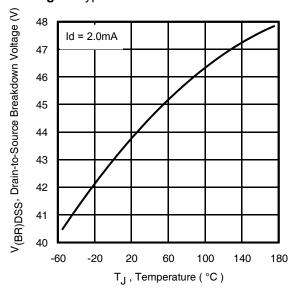


Fig 11. Drain-to-Source Breakdown Voltage

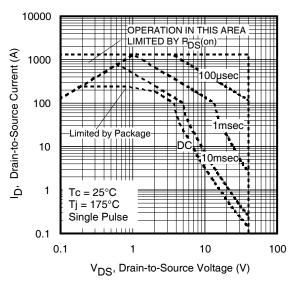


Fig 10. Maximum Safe Operating Area

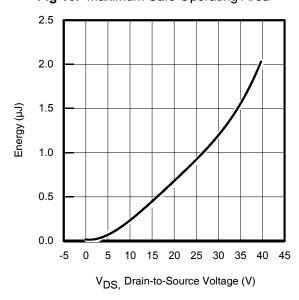


Fig 12. Typical Coss Stored Energy

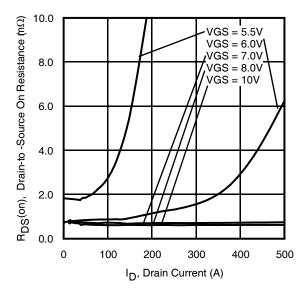


Fig 13. Typical On-Resistance vs. Drain Current



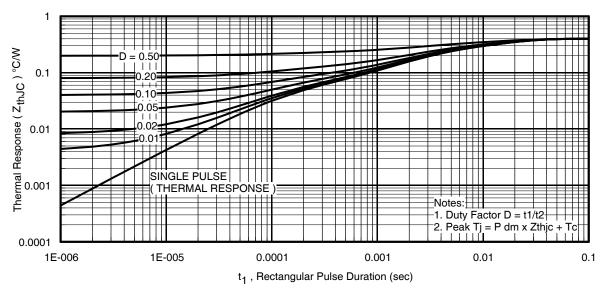


Fig 14. Maximum Effective Transient Thermal Impedance, Junction-to-Case

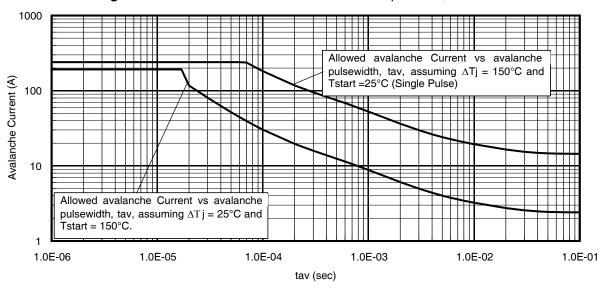


Fig 15. Avalanche Current vs. Pulse width

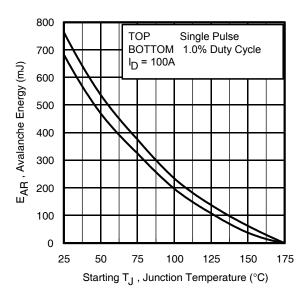


Fig 16. Maximum Avalanche Energy vs. Temperature

### Notes on Repetitive Avalanche Curves, Figures 15, 16: (For further info, see AN-1005 at www.irf.com)

1. Avalanche failures assumption:

Purely a thermal phenomenon and failure occurs at a temperature far in excess of  $T_{\text{jmax}}$ . This is validated for every

- 2. Safe operation in Avalanche is allowed as long  $asT_{j\text{max}}$  is not exceeded.
- 3. Equation below based on circuit and waveforms shown in Figures 23a, 23b.
- 4. P<sub>D (ave)</sub> = Average power dissipation per single avalanche pulse.
- 5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. I<sub>av</sub> = Allowable avalanche current.
- 7.  $\Delta T$  = Allowable rise in junction temperature, not to exceed  $T_{imax}$ (assumed as 25°C in Figure 14, 15).

 $t_{av}$  = Average time in avalanche.

D = Duty cycle in avalanche = tav ·f

 $Z_{thJC}(D, t_{av})$  = Transient thermal resistance, see Figures 13) PD (ave) = 1/2 (  $1.3 \cdot BV \cdot I_{av}$ ) =  $\Delta T / Z_{thJC}$ 

 $I_{av} = 2\Delta T / [1.3 \cdot BV \cdot Z_{th}]$ 



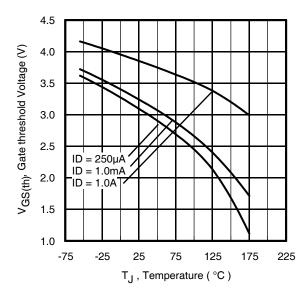


Fig 17. Threshold Voltage vs. Temperature

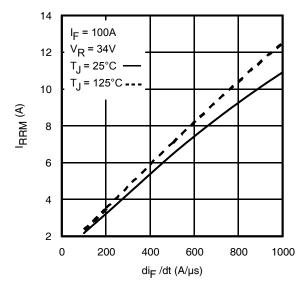


Fig 19. Typical Recovery Current vs. dif/dt

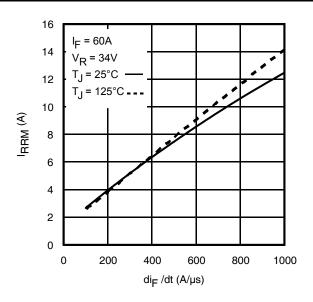


Fig 18. Typical Recovery Current vs. dif/dt

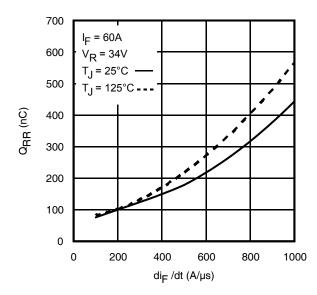


Fig 20. Typical Stored Charge vs. dif/dt

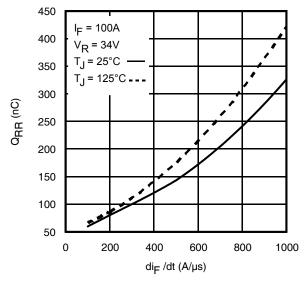


Fig 21. Typical Stored Charge vs. dif/dt



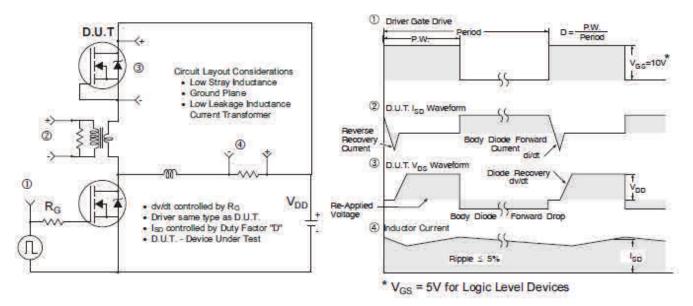


Fig 22. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

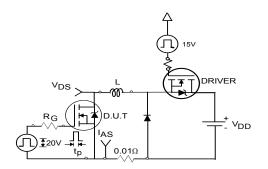


Fig 23a. Unclamped Inductive Test Circuit

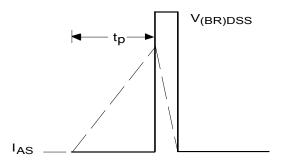


Fig 23b. Unclamped Inductive Waveforms

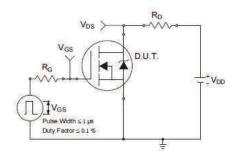


Fig 24a. Switching Time Test Circuit

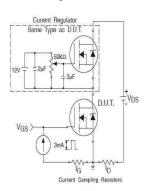


Fig 25a. Gate Charge Test Circuit

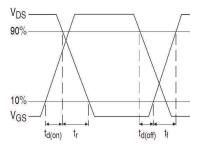


Fig 24b. Switching Time Waveforms

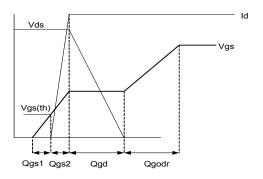
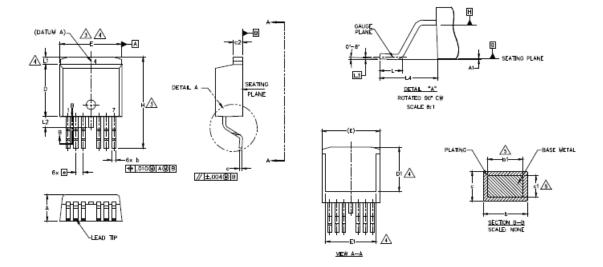


Fig 25b. Gate Charge Waveform



## D<sup>2</sup>Pak-7Pin Package Outline (Dimensions are shown in millimeters (inches))



S W B		Ŋ			
B	MILLIMETERS INCHES			HES	NOTES
L	MIN.	MAX.	MIN.	MAX.	S
Α	4.06	4.83	.160	.190	
A1	-	0,254	_	.010	
ь	0.51	0.99	.020	.036	
b1	0.51	0.89	.020	.032	5
С	0,38	0.74	.015	.029	
c1	0.38	0.58	.015	.023	5
c2	1.14	1.65	.045	.065	
D	8.38	9.65	.330	.380	3
D1	6.86	_	.270		4
Ε	9.65	10.67	.380	.420	3,4
E1	6.22	_	.245		4
е	1,27	1.27 BSC		BSC	
н	14.61	15.88	.575	.625	
L	1.78	2.79	.070	.110	
L1	-	1.68	-	.066	4
L2	-	1.78	_	.070	
L3	0.25	BSC	.010	BSC	
L4	4.78	5.28	.188	.208	

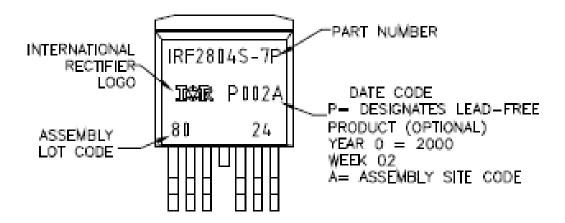
#### NOTES

- 1. DIMENSIONING AND TOLERANCING AS PER ASME Y14.5M-1994
- 2. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].
- O.127 [.005"] PER SIDE. THESE DIMENSIONS ARE MEASURED AT THE OUTMOST EXTREMES OF THE PLASTIC BODY AT DATUM H.
- 4. THERMAL PAD CONTOUR OPTIONAL WITHIN DIMENSION E, L1, D1 & E1.
- 5. DIMENSION 61 AND c1 APPLY TO BASE METAL ONLY.
- 6. DATUM A & B TO BE DETERMINED AT DATUM PLANE H.
- 7, CONTROLLING DIMENSION: INCH.
- 8. OUTLINE CONFORMS TO JEDEC OUTLINE TO-263CB.

Note: For the most current drawing please refer to IR website at <a href="http://www.irf.com/package/">http://www.irf.com/package/</a>



## D<sup>2</sup>Pak-7Pin Part Marking Information



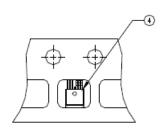
## D2Pak-7Pin Tape and Reel

### NOTES, TAPE & REEL, LABELLING:

- 1. TAPE AND REEL
  - 1.1 REEL SIZE 13 INCH DIAMETER.
  - 1.2 EACH REEL CONTAINING 800 DEVICES.
  - 1.3 THERE SHALL BE A MINIMUM OF 42 SEALED POCKETS CONTAINED IN THE LEADER AND A MINIMUM OF 15 SEALED POCKETS IN THE TRAILER.
  - 1.4 PEEL STRENGTH MUST CONFORM TO THE SPEC. NO.
  - 1.5 PART ORIENTATION SHALL BE AS SHOWN BELOW.
  - 1.6 REEL MAY CONTAIN A MAXIMUM OF TWO UNIQUE REEL MAY COST IN A BRAZING OF THE ORIGINAL LOT CODE /DATE CODE COMBINATIONS.

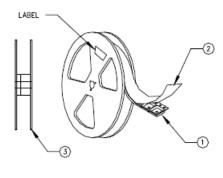
    REWORKED REELS MAY CONTAIN A MAXIMUM OF THREE UNDUE LOT CODE/DATE CODE COMBINATIONS.

    HOWEVER, THE LOT CODES AND DATE CODES WITH THER RESPECTIVE QUANTITIES SHALL APPEAR ON THE BAR CODE LABEL FOR THE AFFECTED REEL.



- 2. LABELLING (REEL AND SHIPPING BAG).
  - 2.1 CUST. PART NUMBER (BAR CODE): IRFXXXXSTRL-7P 2.2 CUST. PART NUMBER (TEXT CODE): IRFXXXXSTRL-7P

  - 2.3 I.R. PART NUMBER: IRFXXXXSTRL-7P
  - 2.4 QUANTITY:
  - 2.5 VENDOR CODE; IR
  - 2.6 LOT CODE:
  - 2.7 DATE CODE:



Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



## Qualification Information<sup>†</sup>

Ovelification Level	Industrial				
Qualification Level	(per JEDEC JESD47F) ††				
Moisture Sensitivity Level	D <sup>2</sup> Pak-7Pin MSL1				
RoHS Compliant	Yes				

- † Qualification standards can be found at International Rectifier's web site: <a href="http://www.irf.com/product-info/reliability/">http://www.irf.com/product-info/reliability/</a>
- †† Applicable version of JEDEC standard at the time of product release.

## **Revision History**

	··· <b>J</b>
Date	Comments
11/6/2014	● Updated E <sub>AS (L =1mH)</sub> = 1454mJ on page 2
11/0/2014	• Updated note 9 "Limited by $T_{Jmax}$ , starting $T_J = 25$ °C, L = 1mH, $R_G = 50\Omega$ , $I_{AS} = 54A$ , $V_{GS} = 10V$ ". on page 2



**IR WORLD HEADQUARTERS:** 101 N. Sepulveda Blvd., El Segundo, California 90245, USA To contact International Rectifier, please visit <a href="http://www.irf.com/whoto-call/">http://www.irf.com/whoto-call/</a>

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